Lattice Semiconductor Corporation - LFE3-95E-8FN484C Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

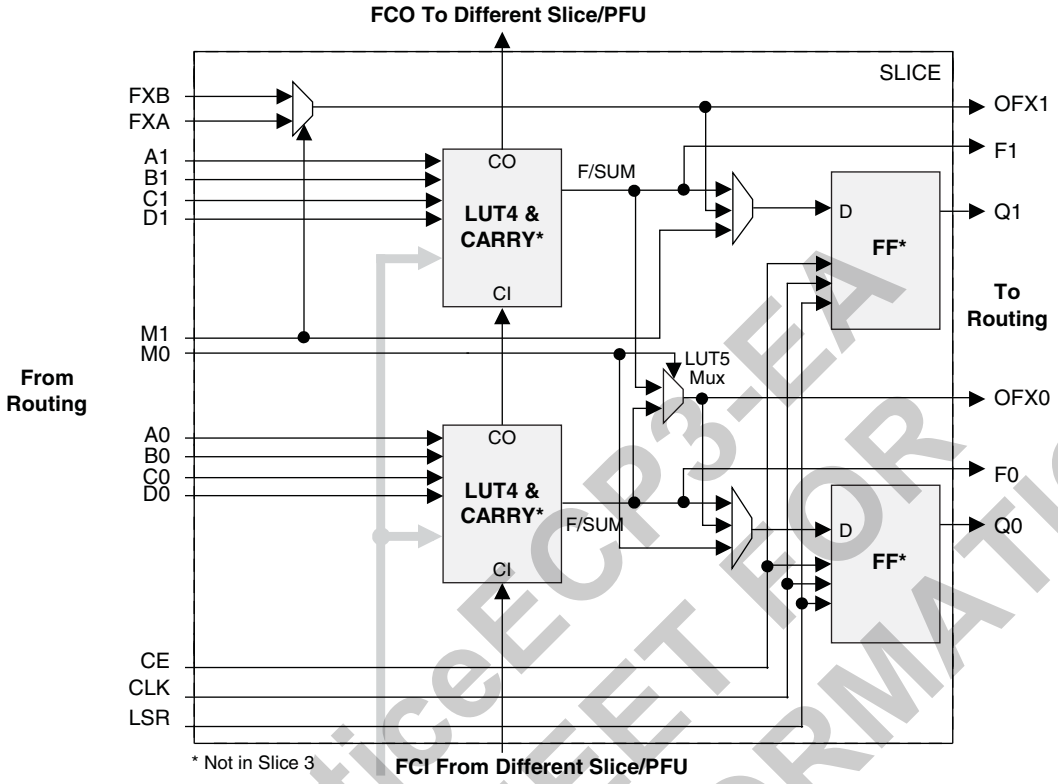
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	11500
Number of Logic Elements/Cells	92000
Total RAM Bits	4526080
Number of I/O	295
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-95e-8fn484c

Figure 2-3. Slice Diagram



For Slices 0 and 1, memory control signals are generated from Slice 2 as follows:

WCK is CLK
WRE is from LSR
DI[3:2] for Slice 1 and DI[1:0] for Slice 0 data from Slice 2
WAD [A:D] is a 4-bit address from slice 2 LUT input

Table 2-2. Slice Signal Descriptions

Function	Type	Signal Names	Description
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4
Input	Multi-purpose	M0	Multipurpose Input
Input	Multi-purpose	M1	Multipurpose Input
Input	Control signal	CE	Clock Enable
Input	Control signal	LSR	Local Set/Reset
Input	Control signal	CLK	System Clock
Input	Inter-PFU signal	FC	Fast Carry-in[1]
Input	Inter-slice signal	FXA	Intermediate signal to generate LUT6 and LUT7
Input	Inter-slice signal	FXB	Intermediate signal to generate LUT6 and LUT7
Output	Data signals	F0, F1	LUT4 output register bypass signals
Output	Data signals	Q0, Q1	Register outputs
Output	Data signals	OFX0	Output of a LUT5 MUX
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8[2] MUX depending on the slice
Output	Inter-PFU signal	FCO	Slice 2 of each PFU is the fast carry chain output[1]

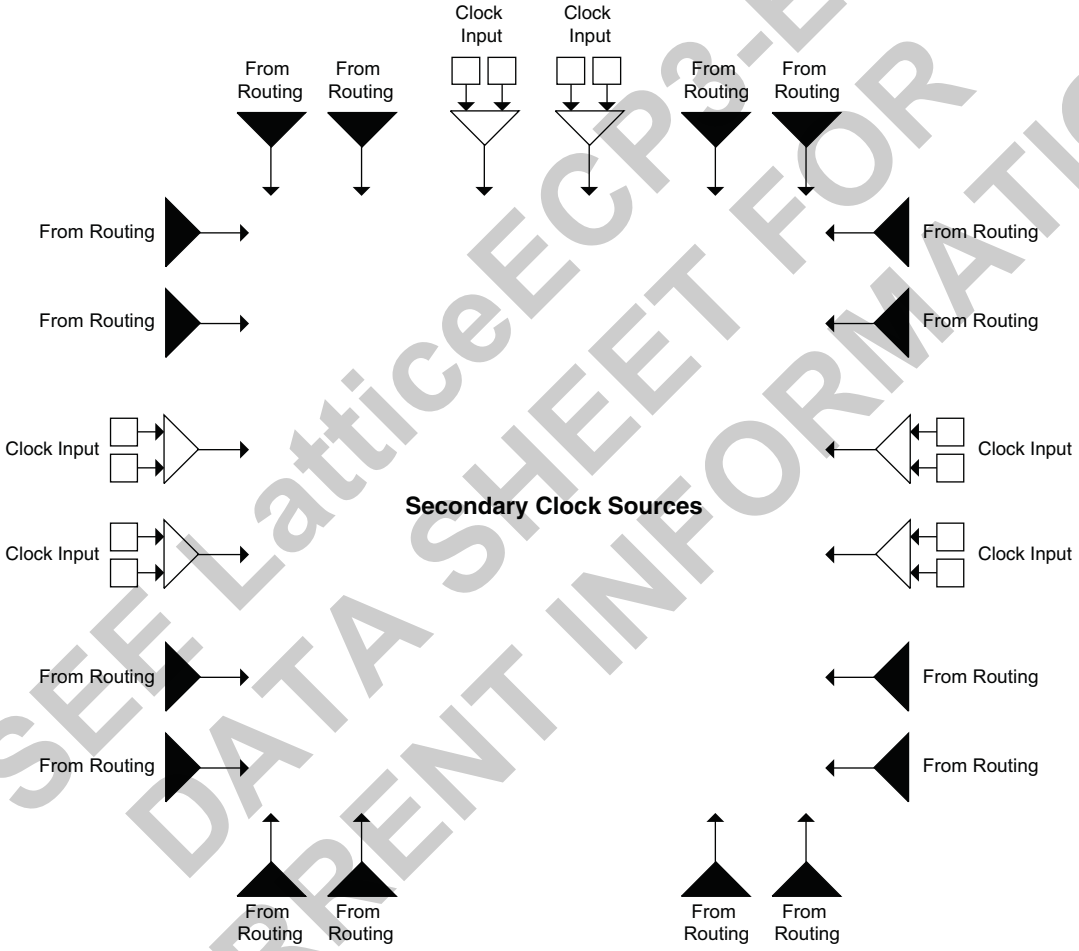
1. See Figure 2-3 for connection details.
2. Requires two PFUs.

Secondary Clock/Control Sources

LatticeECP3 devices derive eight secondary clock sources (SC0 through SC7) from six dedicated clock input pads and the rest from routing. Figure 2-14 shows the secondary clock sources. All eight secondary clock sources are defined as inputs to a per-region mux SC0-SC7. SC0-SC3 are primary for control signals (CE and/or LSR), and SC4-SC7 are for clock and high fanout data.

In an actual implementation, there is some overlap to maximize routability. In addition to SC0-SC3, SC7 is also an input to the control signals (LSR or CE). SC0-SC2 are also inputs to clocks along with SC4-SC7. High fanout logic signals (LUT inputs) will utilize the X2 and X0 switches where SC0-SC7 are inputs to X2 switches, and SC4-SC7 are inputs to X0 switches. Note that through X0 switches, SC4-SC7 can also access control signals CE/LSR.

Figure 2-14. Secondary Clock Sources



Note: Clock inputs can be configured in differential or single-ended mode.

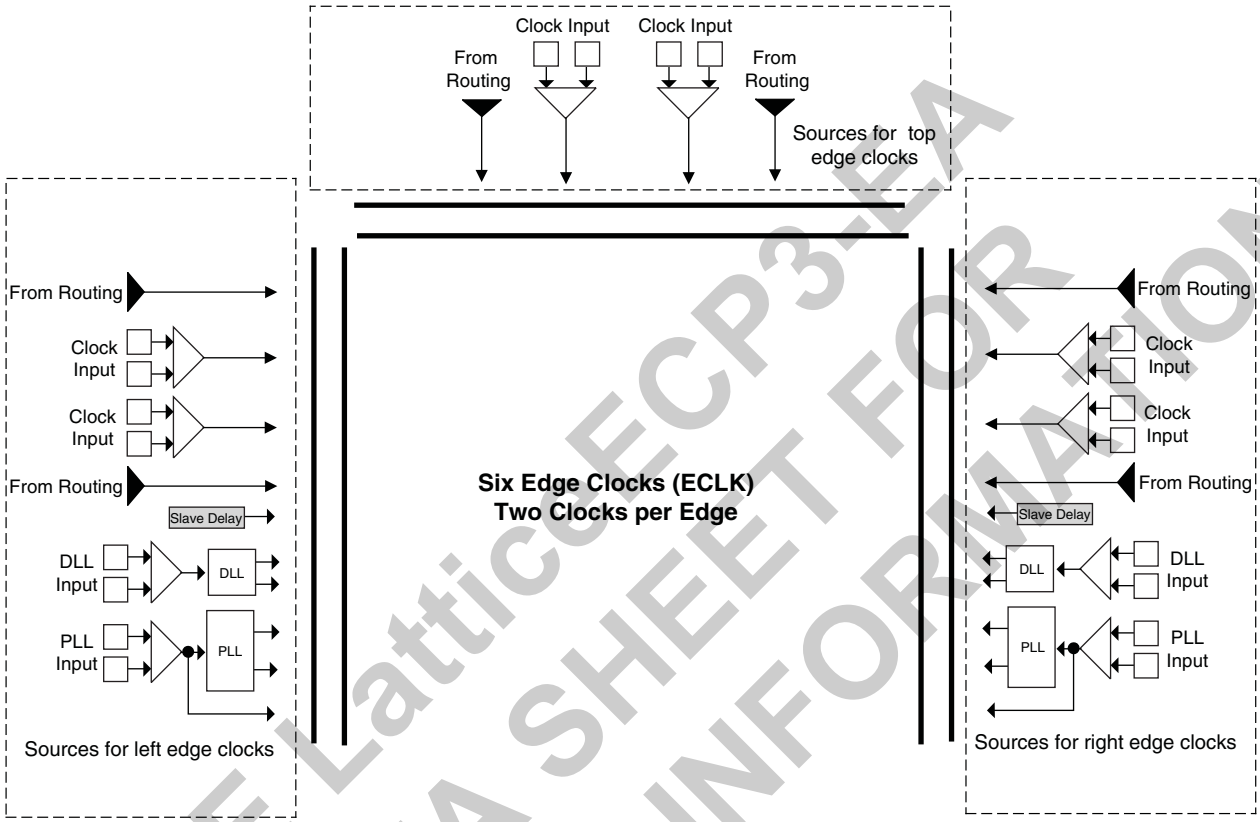
Secondary Clock/Control Routing

Global secondary clock is a secondary clock that is distributed to all regions. The purpose of the secondary clock routing is to distribute the secondary clock sources to the secondary clock regions. Secondary clocks in the LatticeECP3 devices are region-based resources. Certain EBR rows and special vertical routing channels bind the secondary clock regions. This special vertical routing channel aligns with either the left edge of the center DSP slice in the DSP row or the center of the DSP row. Figure 2-15 shows this special vertical routing channel and the 20 secondary clock regions for the LatticeECP3 family of devices. All devices in the LatticeECP3 family have eight

Edge Clock Sources

Edge clock resources can be driven from a variety of sources at the same edge. Edge clock resources can be driven from adjacent edge clock PIOs, primary clock PIOs, PLLs, DLLs, Slave Delay and clock dividers as shown in Figure 2-19.

Figure 2-19. Edge Clock Sources

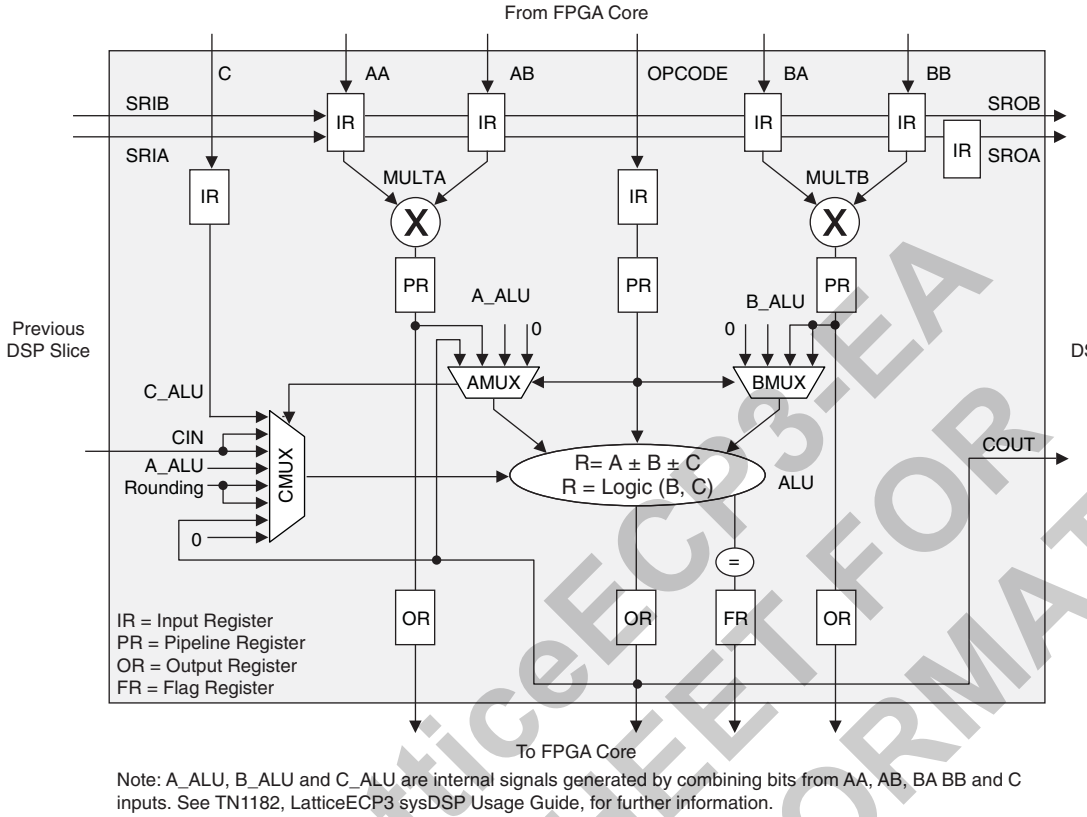


Notes:
1. Clock inputs can be configured in differential or single ended mode.
2. The two DLLs can also drive the two top edge clocks.
3. The top left and top right PLL can also drive the two top edge clocks.

Edge Clock Routing

LatticeECP3 devices have a number of high-speed edge clocks that are intended for use with the PIOs in the implementation of high-speed interfaces. There are six edge clocks per device: two edge clocks on each of the top, left, and right edges. Different PLL and DLL outputs are routed to the two muxes on the left and right sides of the device. In addition, the CLKINDEL signal (generated from the DLL Slave Delay Line block) is routed to all the edge clock muxes on the left and right sides of the device. Figure 2-20 shows the selection muxes for these clocks.

Figure 2-25. Detailed sysDSP Slice Diagram



Note: A_ALU, B_ALU and C_ALU are internal signals generated by combining bits from AA, AB, BA BB and C inputs. See TN1182, LatticeECP3 sysDSP Usage Guide, for further information.

The LatticeECP2 sysDSP block supports the following basic elements.

- MULT (Multiply)
- MAC (Multiply, Accumulate)
- MULTADDSUB (Multiply, Addition/Subtraction)
- MULTADDSUBSUM (Multiply, Addition/Subtraction, Summation)

Table 2-8 shows the capabilities of each of the LatticeECP3 slices versus the above functions.

Table 2-8. Maximum Number of Elements in a Slice

Width of Multiply	x9	x18	x36
MULT	4	2	1/2
MAC	1	1	—
MULTADDSUB	2	1	—
MULTADDSUBSUM	1[1]	1/2	—

1. One slice can implement 1/2 9x9 m9x9addsubsum and two m9x9addsubsum with two slices.

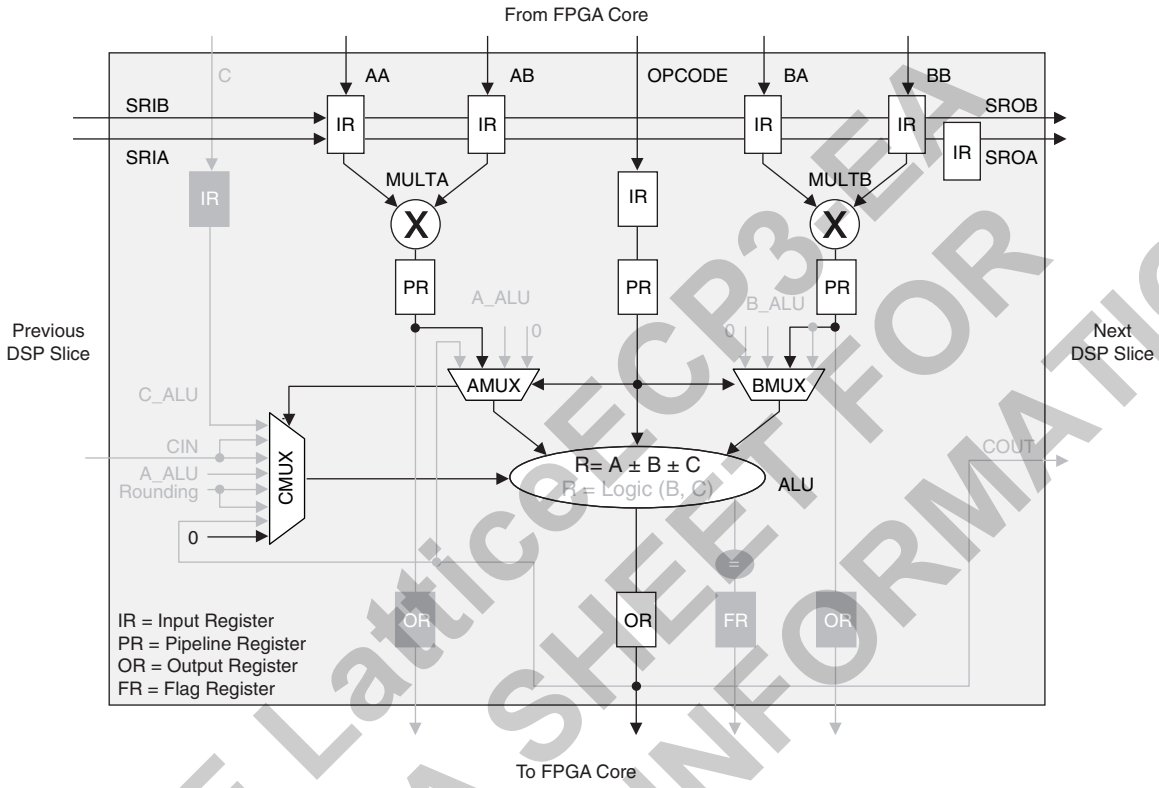
Some options are available in the four elements. The input register in all the elements can be directly loaded or can be loaded as a shift register from previous operand registers. By selecting “dynamic operation” the following operations are possible:

- In the Add/Sub option the Accumulator can be switched between addition and subtraction on every cycle.
- The loading of operands can switch between parallel and serial operations.

MULTADDSUB DSP Element

In this case, the operands AA and AB are multiplied and the result is added/subtracted with the result of the multiplier operation of operands BA and BB. The user can enable the input, output and pipeline registers. Figure 2-29 shows the MULTADDSUB sysDSP element.

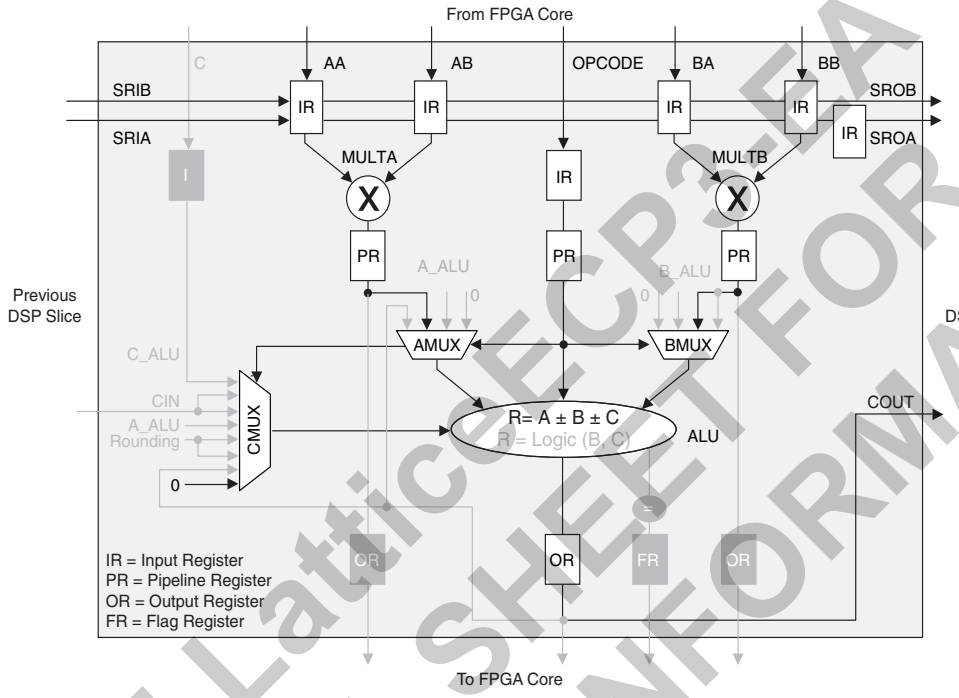
Figure 2-29. MULTADDSUB



MULTADDSUBSUM DSP Element

In this case, the operands AA and AB are multiplied and the result is added/subtracted with the result of the multiplier operation of operands BA and BB of Slice 0. Additionally, the operands AA and AB are multiplied and the result is added/subtracted with the result of the multiplier operation of operands BA and BB of Slice 1. The results of both addition/subtractions are added by the second ALU following the slice cascade path. The user can enable the input, output and pipeline registers. Figure 2-30 and Figure 2-31 show the MULTADDSUBSUM sysDSP element.

Figure 2-30. MULTADDSUBSUM Slice 0



ALU Flags

The sysDSP slice provides a number of flags from the ALU including:

- Equal to zero (EQZ)
- Equal to zero with mask (EQZM)
- Equal to one with mask (EQOM)
- Equal to pattern with mask (EQPAT)
- Equal to bit inverted pattern with mask (EQPATB)
- Accumulator Overflow (OVER)
- Accumulator Underflow (UNDER)
- Either over or under flow supporting LatticeECP2 legacy designs (OVERUNDER)

Clock, Clock Enable and Reset Resources

Global Clock, Clock Enable and Reset signals from routing are available to every sysDSP slice. From four clock sources (CLK0, CLK1, CLK2, and CLK3) one clock is selected for each input register, pipeline register and output register. Similarly Clock Enable (CE) and Reset (RST) are selected at each input register, pipeline register and output register.

Resources Available in the LatticeECP3 Family

Table 2-9 shows the maximum number of multipliers for each member of the LatticeECP3 family. Table 2-10 shows the maximum available EBR RAM Blocks in each LatticeECP3 device. EBR blocks, together with Distributed RAM can be used to store variables locally for fast DSP operations.

Table 2-9. Maximum Number of DSP Slices in the LatticeECP3 Family

Device	DSP Slices	9x9 Multiplier	18x18 Multiplier	36x36 Multiplier
ECP3-17	12	48	24	6
ECP3-35	32	128	64	16
ECP3-70	64	256	128	32
ECP3-95	64	256	128	32
ECP3-150	160	640	320	80

Table 2-10. Embedded SRAM in the LatticeECP3 Family

Device	EBR SRAM Block	Total EBR SRAM (Kbits)
ECP3-17	38	700
ECP3-35	72	1327
ECP3-70	240	4420
ECP3-95	240	4420
ECP3-150	372	6850

Input signals are fed from the sysI/O buffer to the input register block (as signal DI). If desired, the input signal can bypass the register and delay elements and be used directly as a combinatorial signal (INDD), a clock (INCK) and, in selected blocks, the input to the DQS delay block. If an input delay is desired, designers can select either a fixed delay or a dynamic delay DEL[3:0]. The delay, if selected, reduces input register hold time requirements when using a global clock.

The input block allows three modes of operation. In single data rate (SDR) the data is registered with the system clock by one of the registers in the single data rate sync register block.

In DDR mode, two registers are used to sample the data on the positive and negative edges of the modified DQS (ECLKDQSR) in the DDR Memory mode or ECLK signal when using DDR Generic mode, creating two data streams. Before entering the core, these two data streams are synchronized to the system clock to generate two data streams.

A gearbox function can be implemented in each of the input registers on the left and right sides. The gearbox function takes a double data rate signal applied to PIOA and converts it as four data streams, INA, IPA, INB and IPB. The two data streams from the first set of DDR registers are synchronized to the edge clock and then to the system clock before entering the core. Figure 2-30 provides further information on the use of the gearbox function.

The signal DDRCLKPOL controls the polarity of the clock used in the synchronization registers. It ensures adequate timing when data is transferred to the system clock domain from the ECLKDQSR (DDR Memory Interface mode) or ECLK (DDR Generic mode). The DDRLAT signal is used to ensure the data transfer from the synchronization registers to the clock transfer and gearbox registers.

The ECLKDQSR, DDRCLKPOL and DDRLAT signals are generated in the DQS Read Control Logic Block. See Figure 2-37 for an overview of the DQS read control logic.

Further discussion about using the DQS strobe in this module is discussed in the DDR Memory section of this data sheet.

Please see TN1180, LatticeECP3 High-Speed I/O Interface for more information on this topic.

sysI/O Differential Electrical Characteristics

LVDS25

Over Recommended Operating Conditions

Parameter	Description	Test Conditions	Min.	Typ.	Max.	Units
V_{INP}, V_{INM}	Input Voltage		0	—	2.4	V
V_{CM}	Input Common Mode Voltage	Half the Sum of the Two Inputs	0.05	—	2.35	V
V_{THD}	Differential Input Threshold	Difference Between the Two Inputs	+/-100	—	—	mV
I_{IN}	Input Current	Power On or Power Off	—	—	+/-10	µA
V_{OH}	Output High Voltage for V_{OP} or V_{OM}	R_T = 100 Ohm	—	1.38	1.60	V
V_{OL}	Output Low Voltage for V_{OP} or V_{OM}	R_T = 100 Ohm	0.9V	1.03	—	V
V_{OD}	Output Voltage Differential	(V_{OP} - V_{OM}), R_T = 100 Ohm	250	350	450	mV
ΔV_{OD}	Change in V_{OD} Between High and Low		—	—	50	mV
V_{OS}	Output Voltage Offset	(V_{OP} + V_{OM})/2, R_T = 100 Ohm	1.125	1.20	1.375	V
ΔV_{OS}	Change in V_{OS} Between H and L		—	—	50	mV
I_{SAB}	Output Short Circuit Current	V_{OD} = 0V Driver Outputs Shorted to Each Other	—	—	12	mA

Differential HSTL and SSTL

Differential HSTL and SSTL outputs are implemented as a pair of complementary single-ended outputs. All allowable single-ended output classes (class I and class II) are supported in this mode.

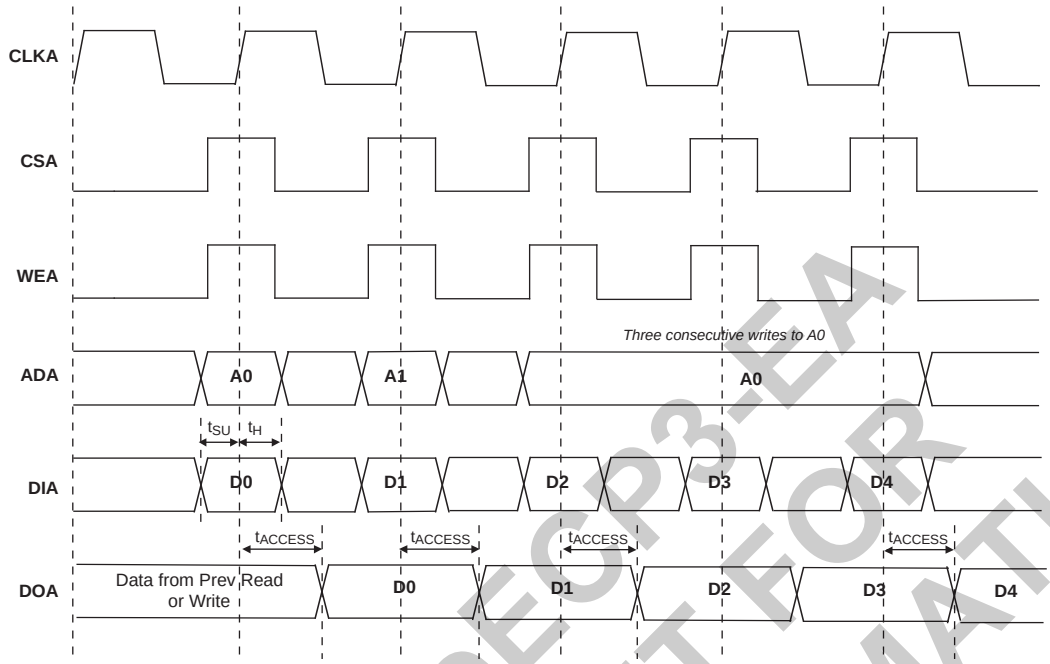
LatticeECP3 Internal Switching Characteristics[1, 2] (Continued)

Over Recommended Commercial Operating Conditions

Parameter	Description	-8		-7		-6		Units.
		Min.	Max.	Min.	Max.	Min.	Max.	
t_{HWREN_EBR}	Hold Write/Read Enable to PFU Memory	0.141	—	0.145	—	0.149	—	ns
t_{SUCE_EBR}	Clock Enable Setup Time to EBR Output Register	0.087		0.096		0.104		ns
t_{HCE_EBR}	Clock Enable Hold Time to EBR Output Register	-0.066		-0.080		-0.094		ns
t_{SUBE_EBR}	Byte Enable Set-Up Time to EBR Output Register	-0.071		-0.070		-0.068		ns
t_{HBE_EBR}	Byte Enable Hold Time to EBR Output Register	0.118		0.098		0.077		ns
DSP Block Timing[3]								
t_{SUI_DSP}	Input Register Setup Time	0.32	—	0.36	—	0.39	—	ns
t_{HI_DSP}	Input Register Hold Time	-0.17	—	-0.19	—	-0.21	—	ns
t_{SUP_DSP}	Pipeline Register Setup Time	2.23	—	2.30	—	2.37	—	ns
t_{HP_DSP}	Pipeline Register Hold Time	-1.02	—	-1.09	—	-1.15	—	ns
t_{SUO_DSP}	Output Register Setup Time	3.09	—	3.22	—	3.34	—	ns
t_{HO_DSP}	Output Register Hold Time	-1.67	—	-1.76	—	-1.84	—	ns
t_{COI_DSP}	Input Register Clock to Output Time	—	3.68	—	4.03	—	4.38	ns
t_{COP_DSP}	Pipeline Register Clock to Output Time	—	1.30	—	1.47	—	1.64	ns
t_{COO_DSP}	Output Register Clock to Output Time	—	0.58	—	0.60	—	0.62	ns
t_{SUOPT_DSP}	Opcode Register Setup Time	0.31	—	0.35	—	0.39	—	ns
t_{HOPT_DSP}	Opcode Register Hold Time	-0.20	—	-0.24	—	-0.27	—	ns
t_{SUDATA_DSP}	Cascade_data through ALU to Output Register Setup Time	1.55	—	1.67	—	1.78	—	ns
t_{HPDATA_DSP}	Cascade_data through ALU to Output Register Hold Time	-0.44	—	-0.53	—	-0.61	—	ns

1. Internal parameters are characterized but not tested on every device.
2. Commercial timing numbers are shown. Industrial timing numbers are typically slower and can be extracted from the ispLEVER software.
3. DSP slice is configured in Multiply Add/Sub 18x18 mode.
4. The output register is in Flip-flop mode.

Figure 3-11. Write Through (SP Read/Write on Port A, Input Registers Only)



Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.

LatticeECP3 Family Timing Adders[1, 2, 3, 4, 5] (Continued)

Over Recommended Commercial Operating Conditions

Buffer Type	Description	-8	-7	-6	Units
RSDS25	RSDS, VCCIO = 2.5V	0.05	0.10	0.16	ns
PPLVDS	Point-to-Point LVDS, Emulated, VCCIO = 2.5V	-0.10	-0.05	0.01	ns
LVPECL33	LVPECL, Emulated, VCCIO = 3.0V	-0.02	-0.04	-0.06	ns
HSTL18_I	HSTL_18 class I 8mA drive, VCCIO = 1.8V	-0.19	-0.16	-0.12	ns
HSTL18_II	HSTL_18 class II, VCCIO = 1.8V	-0.30	-0.28	-0.25	ns
HSTL18D_I	Differential HSTL 18 class I 8mA drive	-0.19	-0.16	-0.12	ns
HSTL18D_II	Differential HSTL 18 class II	-0.30	-0.28	-0.25	ns
HSTL15_I	HSTL_15 class I 4mA drive, VCCIO = 1.5V	-0.22	-0.19	-0.16	ns
HSTL15D_I	Differential HSTL 15 class I 4mA drive	-0.22	-0.19	-0.16	ns
SSTL33_I	SSTL_3 class I, VCCIO = 3.0V	0.08	0.13	0.19	ns
SSTL33_II	SSTL_3 class II, VCCIO = 3.0V	-0.20	-0.17	-0.14	ns
SSTL33D_I	Differential SSTL_3 class I	0.08	0.13	0.18	ns
SSTL33D_II	Differential SSTL_3 class II	-0.20	-0.17	-0.14	ns
SSTL25_I	SSTL_2 class I 8mA drive, VCCIO = 2.5V	-0.06	-0.02	0.02	ns
SSTL25_II	SSTL_2 class II 16mA drive, VCCIO = 2.5V	-0.19	-0.15	-0.12	ns
SSTL25D_I	Differential SSTL_2 class I 8mA drive	-0.06	-0.02	0.02	ns
SSTL25D_II	Differential SSTL_2 class II 16mA drive	-0.19	-0.15	-0.12	ns
SSTL18_I	SSTL_1.8 class I, VCCIO = 1.8V	-0.14	-0.10	-0.07	ns
SSTL18_II	SSTL_1.8 class II 8mA drive, VCCIO = 1.8V	-0.20	-0.17	-0.14	ns
SSTL18D_I	Differential SSTL_1.8 class I	-0.14	-0.10	-0.07	ns
SSTL18D_II	Differential SSTL_1.8 class II 8mA drive	-0.20	-0.17	-0.14	ns
SSTL15	SSTL_1.5, VCCIO = 1.5V	0.07	0.08	0.08	ns
SSTL15D	Differential SSTL_15	0.07	0.08	0.08	ns
LVTTL33_4mA	LVTTL 4mA drive, VCCIO = 3.0V	0.21	0.23	0.25	ns
LVTTL33_8mA	LVTTL 8mA drive, VCCIO = 3.0V	0.09	0.09	0.10	ns
LVTTL33_12mA	LVTTL 12mA drive, VCCIO = 3.0V	0.02	0.03	0.03	ns
LVTTL33_16mA	LVTTL 16mA drive, VCCIO = 3.0V	0.12	0.13	0.13	ns
LVTTL33_20mA	LVTTL 20mA drive, VCCIO = 3.0V	0.08	0.08	0.09	ns
LVCMOS33_4mA	LVCMOS 3.3 4mA drive, fast slew rate	0.21	0.23	0.25	ns
LVCMOS33_8mA	LVCMOS 3.3 8mA drive, fast slew rate	0.09	0.09	0.10	ns
LVCMOS33_12mA	LVCMOS 3.3 12mA drive, fast slew rate	0.02	0.03	0.03	ns
LVCMOS33_16mA	LVCMOS 3.3 16mA drive, fast slew rate	0.12	0.13	0.13	ns
LVCMOS33_20mA	LVCMOS 3.3 20mA drive, fast slew rate	0.08	0.08	0.09	ns
LVCMOS25_4mA	LVCMOS 2.5 4mA drive, fast slew rate	0.12	0.12	0.12	ns
LVCMOS25_8mA	LVCMOS 2.5 8mA drive, fast slew rate	0.05	0.05	0.05	ns
LVCMOS25_12mA	LVCMOS 2.5 12mA drive, fast slew rate	0.00	0.00	0.00	ns
LVCMOS25_16mA	LVCMOS 2.5 16mA drive, fast slew rate	0.08	0.08	0.08	ns
LVCMOS25_20mA	LVCMOS 2.5 20mA drive, fast slew rate	0.04	0.04	0.04	ns
LVCMOS18_4mA	LVCMOS 1.8 4mA drive, fast slew rate	0.08	0.09	0.09	ns
LVCMOS18_8mA	LVCMOS 1.8 8mA drive, fast slew rate	0.02	0.01	0.01	ns
LVCMOS18_12mA	LVCMOS 1.8 12mA drive, fast slew rate	-0.03	-0.03	-0.03	ns
LVCMOS18_16mA	LVCMOS 1.8 16mA drive, fast slew rate	0.03	0.03	0.03	ns

LatticeECP3 Family Timing Adders[1, 2, 3, 4, 5] (Continued)

Over Recommended Commercial Operating Conditions

Buffer Type	Description	-8	-7	-6	Units
LVCMOS15_4mA	LVCMOS 1.5 4mA drive, fast slew rate	0.09	0.10	0.10	ns
LVCMOS15_8mA	LVCMOS 1.5 8mA drive, fast slew rate	0.01	0.01	0.00	ns
LVCMOS12_2mA	LVCMOS 1.2 2mA drive, fast slew rate	0.08	0.08	0.08	ns
LVCMOS12_6mA	LVCMOS 1.2 6mA drive, fast slew rate	-0.02	-0.02	-0.02	ns
LVCMOS33_4mA	LVCMOS 3.3 4mA drive, slow slew rate	1.64	1.71	1.77	ns
LVCMOS33_8mA	LVCMOS 3.3 8mA drive, slow slew rate	1.39	1.45	1.51	ns
LVCMOS33_12mA	LVCMOS 3.3 12mA drive, slow slew rate	1.21	1.27	1.33	ns
LVCMOS33_16mA	LVCMOS 3.3 16mA drive, slow slew rate	1.43	1.49	1.55	ns
LVCMOS33_20mA	LVCMOS 3.3 20mA drive, slow slew rate	1.23	1.28	1.34	ns
LVCMOS25_4mA	LVCMOS 2.5 4mA drive, slow slew rate	1.66	1.70	1.74	ns
LVCMOS25_8mA	LVCMOS 2.5 8mA drive, slow slew rate	1.39	1.43	1.46	ns
LVCMOS25_12mA	LVCMOS 2.5 12mA drive, slow slew rate	1.20	1.24	1.28	ns
LVCMOS25_16mA	LVCMOS 2.5 16mA drive, slow slew rate	1.42	1.45	1.49	ns
LVCMOS25_20mA	LVCMOS 2.5 20mA drive, slow slew rate	1.22	1.26	1.29	ns
LVCMOS18_4mA	LVCMOS 1.8 4mA drive, slow slew rate	1.61	1.65	1.68	ns
LVCMOS18_8mA	LVCMOS 1.8 8mA drive, slow slew rate	1.32	1.36	1.39	ns
LVCMOS18_12mA	LVCMOS 1.8 12mA drive, slow slew rate	1.14	1.17	1.21	ns
LVCMOS18_16mA	LVCMOS 1.8 16mA drive, slow slew rate	1.35	1.38	1.42	ns
LVCMOS15_4mA	LVCMOS 1.5 4mA drive, slow slew rate	1.57	1.60	1.64	ns
LVCMOS15_8mA	LVCMOS 1.5 8mA drive, slow slew rate	0.01	0.01	0.00	ns
LVCMOS12_2mA	LVCMOS 1.2 2mA drive, slow slew rate	1.51	1.54	1.58	ns
LVCMOS12_6mA	LVCMOS 1.2 6mA drive, slow slew rate	-0.02	-0.02	-0.02	ns
PCI33	PCI, VCCIO = 3.0V	0.19	0.21	0.24	ns

1. Timing adders are characterized but not tested on every device.
2. LVCMOS timing measured with the load specified in Switching Test Condition table.
3. All other standards tested according to the appropriate specifications.
4. Not all I/O standards and drive strengths are supported for all banks. See the Architecture section of this data sheet for details.
5. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from the ispLEVER software.

LatticeECP3 Maximum I/O Buffer Speed (Continued)[1, 2, 3, 4, 5, 6]

Over Recommended Operating Conditions

Buffer	Description	Max.	Units
PCI33	PCI, V_{CCIO} = 3.3V	66	MHz

1. These maximum speeds are characterized but not tested on every device.
2. Maximum I/O speed for differential output standards emulated with resistors depends on the layout.
3. LVCMOS timing is measured with the load specified in the Switching Test Conditions table of this document.
4. All speeds are measured at fast slew.
5. Actual system operation may vary depending on user logic implementation.
6. Maximum data rate equals 2 times the clock rate when utilizing DDR.

SERDES High-Speed Data Transmitter[1]

Table 3-6. Serial Output Timing and Levels

Symbol	Description	Frequency	Min.	Typ.	Max.	Units
$V_{TX-DIFF-P-P-1.44}$	Differential swing (1.44V setting)[1, 2]	0.25 to 3.125 Gbps	1150	1440	1730	mV, p-p
$V_{TX-DIFF-P-P-1.35}$	Differential swing (1.35V setting)[1, 2]	0.25 to 3.125 Gbps	1080	1350	1620	mV, p-p
$V_{TX-DIFF-P-P-1.26}$	Differential swing (1.26V setting)[1, 2]	0.25 to 3.125 Gbps	1000	1260	1510	mV, p-p
$V_{TX-DIFF-P-P-1.13}$	Differential swing (1.13V setting)[1, 2]	0.25 to 3.125 Gbps	840	1130	1420	mV, p-p
$V_{TX-DIFF-P-P-1.04}$	Differential swing (1.04V setting)[1, 2]	0.25 to 3.125 Gbps	780	1040	1300	mV, p-p
$V_{TX-DIFF-P-P-0.92}$	Differential swing (0.92V setting)[1, 2]	0.25 to 3.125 Gbps	690	920	1150	mV, p-p
$V_{TX-DIFF-P-P-0.87}$	Differential swing (0.87V setting)[1, 2]	0.25 to 3.125 Gbps	650	870	1090	mV, p-p
$V_{TX-DIFF-P-P-0.78}$	Differential swing (0.78V setting)[1, 2]	0.25 to 3.125 Gbps	585	780	975	mV, p-p
$V_{TX-DIFF-P-P-0.64}$	Differential swing (0.64V setting)[1, 2]	0.25 to 3.125 Gbps	480	640	800	mV, p-p
V_{OCM}	Output common mode voltage	—	V_{CCOB} -0.75	V_{CCOB} -0.60	V_{CCOB} -0.45	V
T_{TX-R}	Rise time (20% to 80%)	—	145	185	265	ps
T_{TX-F}	Fall time (80% to 20%)	—	145	185	265	ps
$Z_{TX-OI-SE}$	Output Impedance 50/75/HiZ Ohms (single ended)	—	-20%	50/75/ Hi Z	+20%	Ohms
R_{LTX-RL}	Return loss (with package)	—	10			dB
$T_{TX-INTRASKEW}$	Lane-to-lane TX skew within a SERDES quad block (intra-quad)	—	—	—	200	ps
$T_{TX-INTERSKEW}$[3]	Lane-to-lane skew between SERDES quad blocks (inter-quad)	—	—	—	1UI +200	ps

1. All measurements are with 50 ohm impedance.
2. See TN1176, LatticeECP3 SERDES/PCS Usage Guide for actual binary settings and the min-max range.
3. Inter-quad skew is between all SERDES channels on the device and requires the use of a low skew internal reference clock.

Table 3-7. Channel Output Jitter

Description	Frequency	Min.	Typ.	Max.	Units
Deterministic	3.125 Gbps	—	—	0.17	UI, p-p
Random	3.125 Gbps	—	—	0.25	UI, p-p
Total	3.125 Gbps	—	—	0.35	UI, p-p
Deterministic	2.5Gbps	—	—	0.17	UI, p-p
Random	2.5Gbps	—	—	0.20	UI, p-p
Total	2.5Gbps	—	—	0.35	UI, p-p
Deterministic	1.25 Gbps	—	—	0.10	UI, p-p
Random	1.25 Gbps	—	—	0.22	UI, p-p
Total	1.25 Gbps	—	—	0.24	UI, p-p
Deterministic	622 Mbps	—	—	0.10	UI, p-p
Random	622 Mbps	—	—	0.20	UI, p-p
Total	622 Mbps	—	—	0.24	UI, p-p
Deterministic	250 Mbps	—	—	0.10	UI, p-p
Random	250 Mbps	—	—	0.18	UI, p-p
Total	250 Mbps	—	—	0.24	UI, p-p

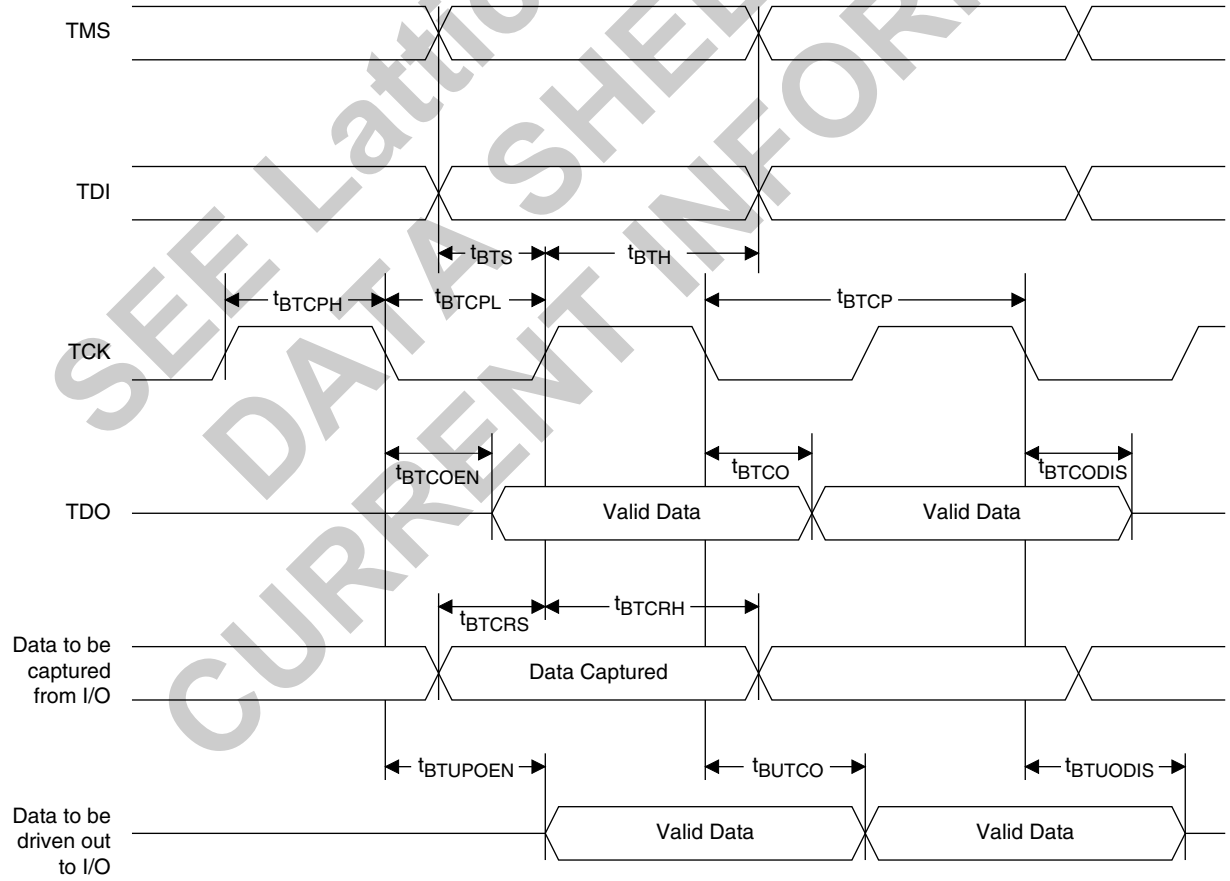
Note: Values are measured with PRBS 2^7-1, all channels operating, FPGA logic active, I/Os around SERDES pins quiet, reference clock @ 10X mode.

JTAG Port Timing Specifications

Over Recommended Operating Conditions

Symbol	Parameter	Min	Max	Units
f_{MAX}	TCK clock frequency	—	25	MHz
t_{BTCP}	TCK [BSCAN] clock pulse width	40	—	ns
t_{BTCPH}	TCK [BSCAN] clock pulse width high	20	—	ns
t_{BTCPL}	TCK [BSCAN] clock pulse width low	20	—	ns
t_{BTS}	TCK [BSCAN] setup time	10	—	ns
t_{BTH}	TCK [BSCAN] hold time	8	—	ns
t_{BTRF}	TCK [BSCAN] rise/fall time	50	—	mV/ns
t_{BTCO}	TAP controller falling edge of clock to valid output	—	10	ns
$t_{BTCODIS}$	TAP controller falling edge of clock to valid disable	—	10	ns
t_{BTCOEN}	TAP controller falling edge of clock to valid enable	—	10	ns
t_{BTCRS}	BSCAN test capture register setup time	8	—	ns
t_{BTCRH}	BSCAN test capture register hold time	25	—	ns
t_{BUTCO}	BSCAN test update register, falling edge of clock to valid output	—	25	ns
$t_{BTUODIS}$	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
$t_{BTUPOEN}$	BSCAN test update register, falling edge of clock to valid enable	—	25	ns

Figure 3-25. JTAG Port Timing Waveforms



Point-to-Point LVDS (PPLVDS)

Over Recommended Operating Conditions

Description	Min.	Typ.	Max.	Units
Output driver supply (+/- 5%)	3.14	3.3	3.47	V
	2.25	2.5	2.75	V
Input differential voltage	100		400	mV
Input common mode voltage	0.2		2.3	V
Output differential voltage	130		400	mV
Output common mode voltage	0.5	0.8	1.4	V

RSDS

Over Recommended Operating Conditions

Parameter Symbol	Description	Min.	Typ.	Max.	Units
V_{OD}	Output voltage, differential, R_T = 100 ohms	100	200	600	mV
V_{OS}	Output voltage, common mode	0.5	1.2	1.5	V
I_{RSDS}	Differential driver output current	1	2	6	mA
V_{THD}	Input voltage differential	100	—	—	mV
V_{CM}	Input common mode voltage	0.3	—	1.5	V
T_R, T_F	Output rise and fall times, 20% to 80%	—	500	—	ps
T_{ODUTY}	Output clock duty cycle	35	50	65	%

Note: Data is for 2mA drive. Other differential driver current options are available.

Signal Descriptions (Cont.)

Signal Name	I/O	Description
D7/SPID0	I/O	Parallel configuration I/O. SPI/SPIm data input. Open drain during configuration.
DI/CSSPI0N/CEN	I/O	Serial data input for slave serial mode. SPI/SPIm mode chip select.
Dedicated SERDES Signals[2]		
PCS[Index]_HDINNm	I	High-speed input, negative channel m
PCS[Index]_HDOUTNm	O	High-speed output, negative channel m
PCS[Index]_REFCLKN	I	Negative Reference Clock Input
PCS[Index]_HDINPm	I	High-speed input, positive channel m
PCS[Index]_HDOUTPm	O	High-speed output, positive channel m
PCS[Index]_REFCLKP	I	Positive Reference Clock Input
PCS[Index]_VCCOBm	—	Output buffer power supply, channel m (1.2V/1.5)
PCS[Index]_VCCIBm	—	Input buffer power supply, channel m (1.2V/1.5V)

1. When placing switching I/Os around these critical pins that are designed to supply the device with the proper reference or supply voltage, care must be given.
2. m defines the associated channel in the quad.

Pin Information Summary (Cont.)

Pin Information Summary		ECP3-17EA		ECP3-35EA		
Pin Type		256 ftBGA	484 fpBGA	256 ftBGA	484 fpBGA	672 fpBGA
Emulated Differential I/O per Bank	Bank 0	13	18	13	21	24
	Bank 1	7	12	7	18	18
	Bank 2	2	4	1	8	8
	Bank 3	4	13	5	20	19
	Bank 6	5	13	6	22	20
	Bank 7	6	10	6	11	13
	Bank 8	12	12	12	12	12
Highspeed Differential I/O per Bank	Bank 0	0	0	0	0	0
	Bank 1	0	0	0	0	0
	Bank 2	2	3	3	6	6
	Bank 3	5	9	4	9	12
	Bank 6	5	9	4	11	12
	Bank 7	5	8	5	9	10
	Bank 8	0	0	0	0	0
Total Single Ended/ Total Differential I/O per Bank	Bank 0	26/13	36/18	26/13	42/21	48/24
	Bank 1	14/7	24/12	14/7	36/18	36/18
	Bank 2	8/4	14/7	8/4	28/14	28/14
	Bank 3	18/9	44/22	18/9	58/29	63/31
	Bank 6	20/10	44/22	20/10	67/33	65/32
	Bank 7	23/11	36/18	23/11	40/20	46/23
	Bank 8	24/12	24/12	24/12	24/12	24/12
DDR Groups Bonded per Bank	Bank 0	2	3	2	3	4
	Bank 1	1	2	1	3	3
	Bank 2	0	1	0	2	2
	Bank 3	1	3	1	3	4
	Bank 6	1	3	1	4	4
	Bank 7	1	2	1	3	3
	Configuration Bank 8	0	0	0	0	0
SERDES Quads		1	1	1	1	1

1. These pins must remain floating on the board.

Pin Information Summary (Cont.)

Pin Information Summary		ECP3-70E			ECP3-70EA		
Pin Type		484 fpBGA	672 fpBGA	1156 fpBGA	484 fpBGA	672 fpBGA	1156 fpBGA
Emulated Differential I/O per Bank	Bank 0	21	30	43	21	30	43
	Bank 1	18	24	39	18	24	39
	Bank 2	10	15	16	8	12	13
	Bank 3	23	27	39	20	23	33
	Bank 6	26	30	39	22	25	33
	Bank 7	14	20	22	11	16	18
	Bank 8	12	12	12	12	12	12
High-Speed Differential I/O per Bank	Bank 0	0	0	0	0	0	0
	Bank 1	0	0	0	0	0	0
	Bank 2	4	6	6	6	9	9
	Bank 3	6	8	10	9	12	16
	Bank 6	7	9	10	11	14	16
	Bank 7	6	8	9	9	12	13
	Bank 8	0	0	0	0	0	0
Total Single-Ended/ Total Differential I/O per Bank	Bank 0	42/21	60/30	86/43	42/21	60/30	86/43
	Bank 1	36/18	48/24	78/39	36/18	48/24	78/39
	Bank 2	28/14	42/21	44/22	28/14	42/21	44/22
	Bank 3	58/29	71/35	98/49	58/29	71/35	98/49
	Bank 6	67/33	79/38	98/49	67/33	78/39	98/49
	Bank 7	40/20	56/28	62/31	40/20	56/28	62/31
	Bank 8	24/12	24/12	24/12	24/12	24/12	24/12
DDR Groups Bonded per Bank	Bank 0	3	5	7	3	5	7
	Bank 1	3	4	7	3	4	7
	Bank 2	2	3	3	2	3	3
	Bank 3	3	4	5	3	4	5
	Bank 6	4	4	5	4	4	5
	Bank 7	3	4	4	3	4	4
	Configuration Bank 8	0	0	0	0	0	0
SERDES Quads		1	2	3	1	2	3